

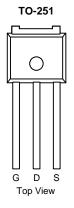
## SSU80R1K3S-VB Datasheet

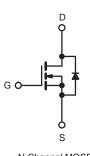
## N-Channel 800V (D-S)Super Junction Power MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	800					
R <sub>DS(on)</sub> (Ω)	$V_{GS} = 10 V$	1.2				
Q <sub>g</sub> (Max.) (nC)	200					
Q <sub>gs</sub> (nC)	24					
Q <sub>gd</sub> (nC)	110					
Configuration	Single					

### **FEATURES**

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS (T</b> C	= 25 °C, unl	ess otherwis	se noted)				
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			V <sub>DS</sub>	800	- V		
Gate-Source Voltage			V <sub>GS</sub>	± 20			
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{C} = 25 \text{ °C}$ $T_{C} = 100 \text{ °C}$	I <sub>D</sub>	5			
	VGS at 10 V			3.9	A		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	21	1		
Linear Derating Factor				1.5	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	770	mJ		
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	7.8	A		
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	19	mJ		
Maximum Power Dissipation	T <sub>C</sub> =	25 °C	PD	190	W		
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	2.0	V/ns		
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	℃		
Soldering Recommendations (Peak Temperature)	for 10 s			300 <sup>d</sup>			
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in		
				1.1	N · m		

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 50 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 23 mH,  $R_g = 25 \Omega$ ,  $I_{AS} = 7.8 \text{ A}$  (see fig. 12). c.  $I_{SD} \leq 7.8 \text{ A}$ , dl/dt  $\leq 140 \text{ A/}\mu\text{s}$ ,  $V_{DD} \leq 600 \text{ V}$ ,  $T_J \leq 150 \text{ °C}$ .

d. 1.6 mm from case.

\* Pb containing terminations are not RoHS compliant, exemptions may apply

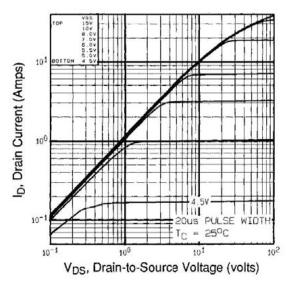


THERMAL RESISTANCE RATII	NGS								
PARAMETER	SYMBOL	TYP. MAX		MAX.		UNIT			
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 40 0.24 -							
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>			°C/W		°C/W			
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 0.65							
<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C, u	nless otherwi	se noted)							
PARAMETER	SYMBOL		T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT	
Static								1	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> =	250 µA	800	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I <sub>D</sub> = 1 mA	-	0.98	-	V/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$			2.0	-	4.0	V	
Gate-Source Leakage	I <sub>GSS</sub>		$V_{GS} = \pm 20 \text{ V}$			-	± 100	nA	
		V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V		<sub>as</sub> = 0 V	-	-	100	<u> </u>	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 640 \	/, V <sub>GS</sub> = 0 V	V, T <sub>J</sub> = 125 °C	-	-	500	μA	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V		<sub>0</sub> = 3.7 A <sup>b</sup>	-	1.2	-	Ω	
Forward Transconductance	<b>g</b> <sub>fs</sub>	V <sub>DS</sub> =	100 V, I <sub>D</sub>	= 3.7 A <sup>b</sup>	5.6	-	-	S	
Dynamic									
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 \	/	-	3100	-	pF	
Output Capacitance	C <sub>oss</sub>		$V_{DS} = 25$	V,	-	800	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1	f = 1.0 MHz, see fig. 5		-	490	-		
Total Gate Charge	Qg			-	-	200			
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	l <sub>D</sub> = 3.8	A, $V_{DS} = 400 V$ , ig. 6 and $13^{b}$	-	-	24	nC	
Gate-Drain Charge	Q <sub>gd</sub>	-	366 1	ig. 0 and 10	-	-	110		
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 3.8 \text{ A},$ $R_{g} = 6.2 \Omega, R_{D} = 52 \Omega$		-	19	-	ns		
Rise Time	tr			-	38	-			
Turn-Off Delay Time	t <sub>d(off)</sub>			-	120	-			
Fall Time	t <sub>f</sub>	see fig. 10 <sup>b</sup>			-	39		-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from		-	5.0	-	nH		
Internal Source Inductance	L <sub>S</sub>	die contact			-	13		-	
Drain-Source Body Diode Characteristic	S								
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the		-	-	5.0	A		
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode			-	-		21	
Body Diode Voltage	V <sub>SD</sub>	$T_{J} = 25 \text{ °C}, I_{S} = 3.8 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.8	V		
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_{\rm J} = 25 ^{\circ}{\rm C},  I_{\rm F} = 3.8  {\rm A}, \ {\rm dl/dt} = 100  {\rm A/\mu s^b}$		-	650	980	ns		
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	3.8	5.7	μC		
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	rn-on time	is negligible (turn	-on is dor	minated b	by $L_{S}$ and	L <sub>D</sub> )	

#### Notes

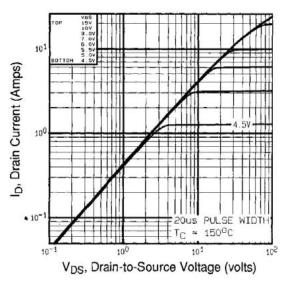
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)







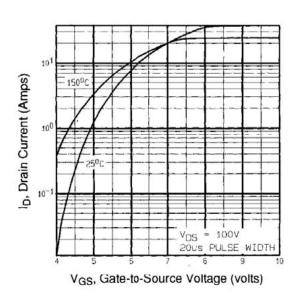
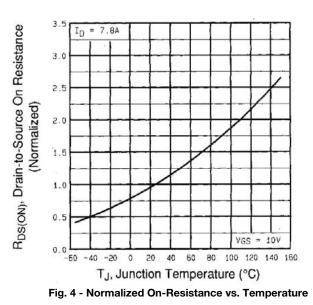


Fig. 3 - Typical Transfer Characteristics



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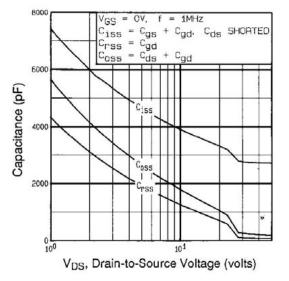
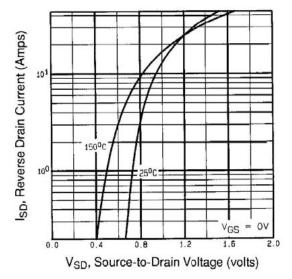


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage





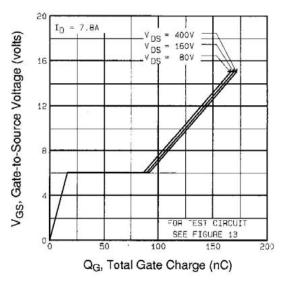
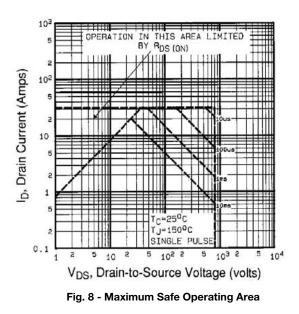


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



## SSU80R1K3S-VB



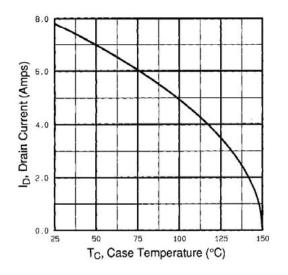


Fig. 9 - Maximum Drain Current vs. Case Temperature

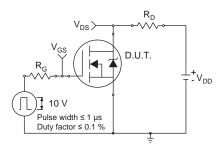


Fig. 10a - Switching Time Test Circuit

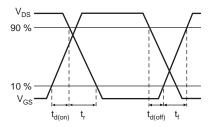


Fig. 10b - Switching Time Waveforms

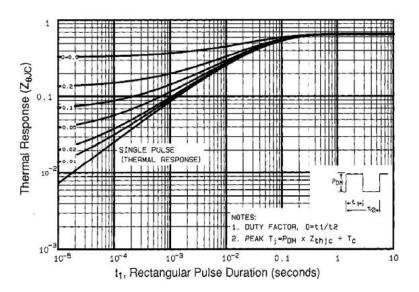


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



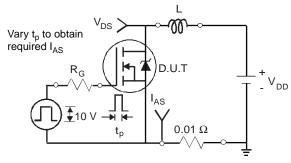


Fig. 12a - Unclamped Inductive Test Circuit

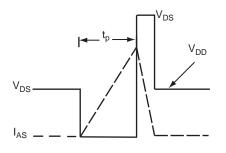


Fig. 12b - Unclamped Inductive Waveforms

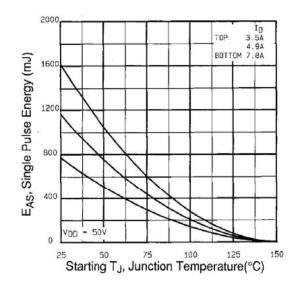


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

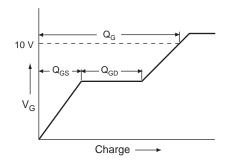


Fig. 13a - Basic Gate Charge Waveform

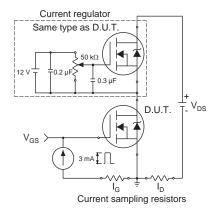
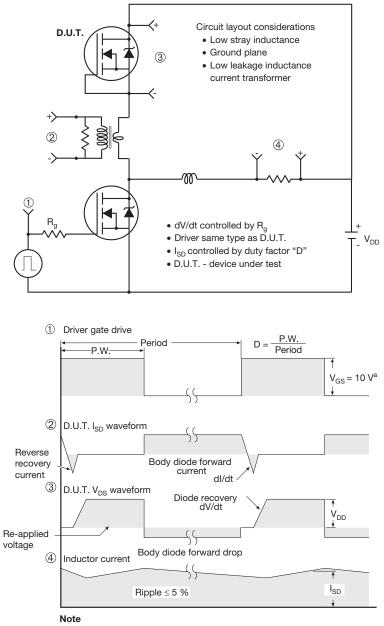


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



a.  $V_{GS} = 5 V$  for logic level devices

Fig. 14 - For N-Channel



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